



InAsSb photovoltaic detector

P11120-201

High-speed response and high sensitivity in the 5 μ m spectral band Thermoelectrically cooled infrared detector with no liquid nitrogen required

The P11120-201 is an infrared detector that provides high sensitivity in the 5 μ m spectral band due to our unique crystal growth technology. The InAsSb photovoltaic detector has a PN junction that ensures high-speed response and high reliability. Typical applications include gas analysis such as CO₂, SO_x, CO and NO_x. The P11120-201 is environmentally friendly infrared detector and do not use lead, mercury or cadmium, which are substances restricted by the RoHS Directive. They are replacements for previous products that contain these substances.

Features

High-speed response

- High sensitivity
- High reliability
- RoHS compliant

- Applications

- Gas analysis
- Radiation thermometers
- Thermal imaging
- Remote sensing
- → FTIR
- Spectrophotometry

Options (sold separately)

Heatsink for two-stage TE-cooled type	A3179-01
Temperature controller	C1103-04
Amplifier for infrared detector	C4159-07
Infrared detector module with preamp	C12494-210S

Structure

Parameter	Specification	Unit
Window material	Sapphire	-
Package	TO-8	-
Cooling	Two-stage TE-cooled	-
Photosensitive area	φ1.0	mm

Absolute maximum ratings

Parameter	Symbol	Value	Unit
Thermistor power dissipation	-	0.2	mW
Reverse voltage	VR	0.1	V
Operating temperature*1 *2	Topr	-40 to +60	°C
Storage temperature*1	Tstg	-55 to +60	°C

*1: No dew condensation

When there is a temperature difference between a product and the surounding area in high humidity environment, dew condensation may occur on the product surface. Dew condensation on the product may cause deterioration in characteristics and relaiablity.

*2: Chip temperature and package temperature

Note: Exceeding the absolute maximum ratings even momentarily may cause a drop in product quality. Always be sure to use the product within the absolute maximum ratings.

Spectral response

(Typ. Tchip=-30 °C)

5

6

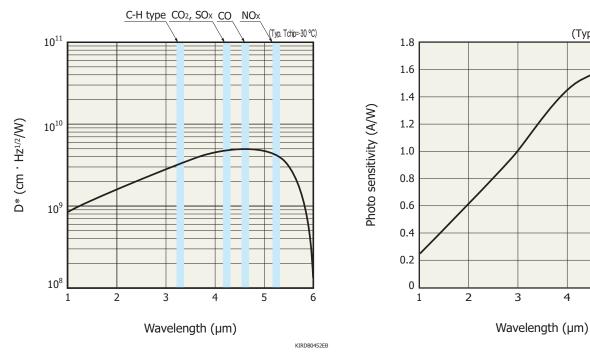
KIRDB0453EB

4

Parameter	Symbol	Condition	Min.	Тур.	Max.	Unit
Peak sensitivity wavelength	λр		4.0	4.9	-	μm
Cutoff wavelength	λc		5.6	5.9	-	μm
Photo sensitivity	S	λ=λp	0.8	1.6	-	A/W
Shunt resistance	Rsh	VR=10 mV	10	13	-	Ω
Detectivity	D*	(λp, 1200, 1)	3.5×10^{9}	5.0×10^{9}	-	cm·Hz ^{1/2} /W
Noise equivalent power	NEP	λ=λp	-	1.8×10^{-11}	2.5×10^{-11}	W/Hz ^{1/2}
Rise time	tr	VR=0 V, RL=50 Ω 0 to 63%	-	0.4	-	μs

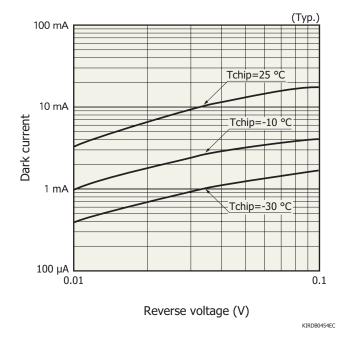
Electrical and optical characteristics (Tchip=-30 °C)



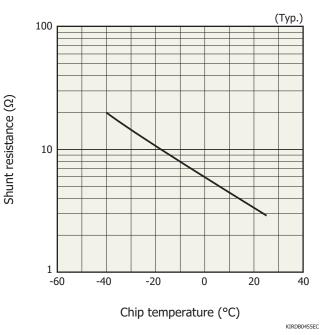




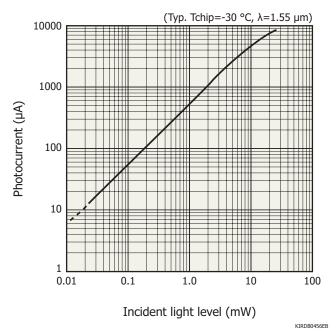
Dark current vs. reverse voltage



- Shunt resistance vs. chip temperature



Linearity

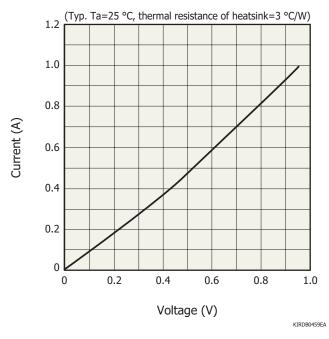




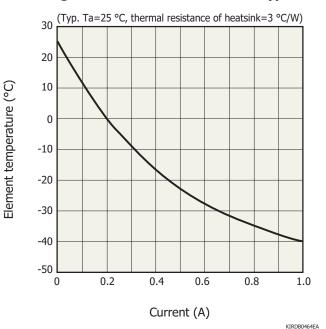
Specifications of two-stage TE-cooler (Ta=25 °C)

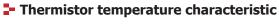
Parameter	Symbol	Min.	Тур.	Max.	Unit
Allowable current	Ic	-	-	1.0	A
Allowable voltage	Vc	-	-	0.95	V
Thermistor resistance	Rth	8.1	9.0	9.9	kΩ
Thermistor power dissipation	Pth	-	-	0.2	mW

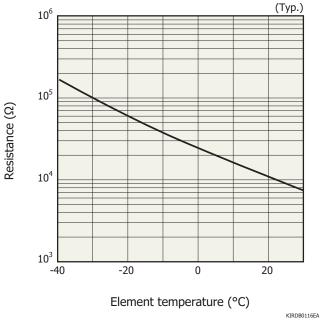
Current vs. voltage of TE-cooled type



Cooling characteristics of TE-cooled type

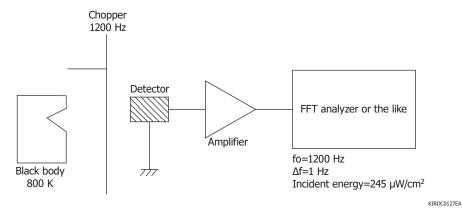




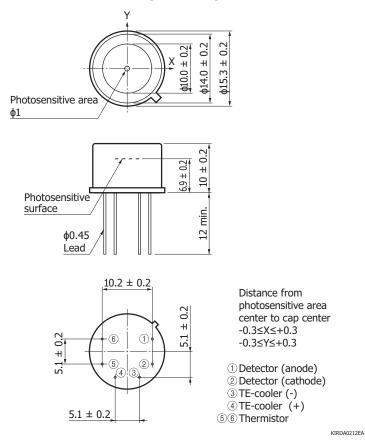




Measurement circuit example



Dimensional outline (unit: mm)



Recommended soldering conditions

 \cdot Solder temperature: 260 °C (10 s or less, once) Note: When you set soldering conditions, check that problems do not occur in the product by testing out the conditions in advance.



Related information

www.hamamatsu.com/sp/ssd/doc_en.html

- Precautions
 - Dislaimer
 - · Compound opto-semiconductors

Technical note

· Compound semiconductor photosensors

Information described in this material is current as of October 2023.

Product specifications are subject to change without prior notice due to improvements or other reasons. This document has been carefully prepared and the information contained is believed to be accurate. In rare cases, however, there may be inaccuracies such as text errors. Before using these products, always contact us for the delivery specification sheet to check the latest specifications.

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